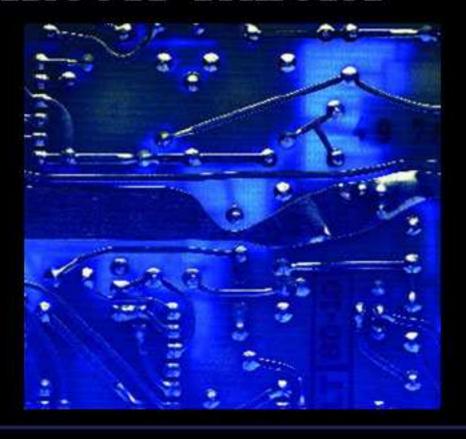
# ELECTRONIC DEVICES AND CIRCUIT THEORY

TENTH EDITION

**BOYLESTAD** 





Chapter 6: Field-Effect Transistors

#### FETs vs. BJTs

#### Similarities:

Amplifiers

Electronic Devices and Circuit Theory, 10/e

Robert L. Boylestad and Louis Nashelsky

- Switching devices
- Impedance matching circuits

#### **Differences:**

- FETs are voltage controlled devices. BJTs are current controlled devices.
- FETs have a higher input impedance. BJTs have higher gains.
- FETs are less sensitive to temperature variations and are more easily integrated on ICs.
- FETs are generally more static sensitive than BJTs.

### **FET Types**

•JFET: Junction FET

•MOSFET: Metal-Oxide-Semiconductor FET

**D-MOSFET:** Depletion MOSFET

**E-MOSFET**: Enhancement MOSFET

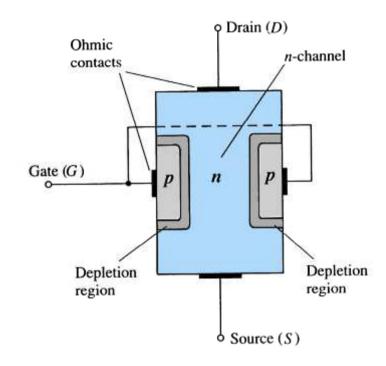


### **JFET Construction**

There are two types of JFETs

- •n-channel
- •p-channel

The n-channel is more widely used.



There are three terminals:

- **•Drain** (D) and Source (S) are connected to the *n*-channel
- •Gate (G) is connected to the *p*-type material

# JFET Operation: The Basic Idea

JFET operation can be compared to a water spigot.

The source of water pressure is the accumulation of electrons at the negative pole of the drain-source voltage.

The drain of water is the electron deficiency (or holes) at the positive pole of the applied voltage.

The control of flow of water is the gate voltage that controls the width of the n-channel and, therefore, the flow of charges from source to drain.



### JFET Operating Characteristics

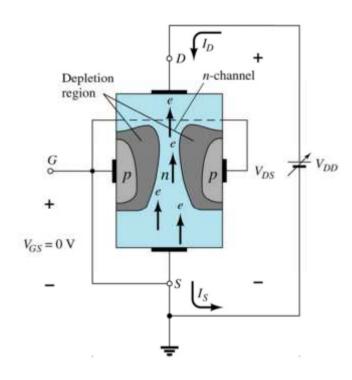
There are three basic operating conditions for a JFET:

- V<sub>GS</sub> = 0, V<sub>DS</sub> increasing to some positive value
- V<sub>GS</sub> < 0, V<sub>DS</sub> at some positive value
- Voltage-controlled resistor

### JFET Operating Characteristics: $V_{GS} = 0 \text{ V}$

Three things happen when  $V_{GS} = 0$  and  $V_{DS}$  is increased from 0 to a more positive voltage

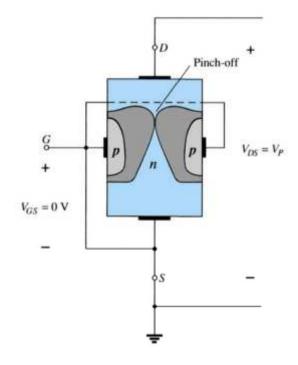
- The depletion region between p-gate and n-channel increases as electrons from n-channel combine with holes from p-gate.
- Increasing the depletion region, decreases the size of the n-channel which increases the resistance of the n-channel.
- Even though the n-channel resistance is increasing, the current  $(I_D)$  from source to drain through the n-channel is increasing. This is because  $V_{DS}$  is increasing.



### JFET Operating Characteristics: Pinch Off

If  $V_{GS} = 0$  and  $V_{DS}$  is further increased to a more positive voltage, then the depletion zone gets so large that it pinches off the n-channel.

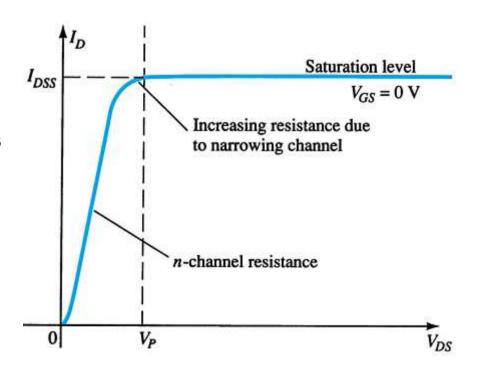
This suggests that the current in the n-channel ( $I_D$ ) would drop to 0A, but it does just the opposite—as  $V_{DS}$  increases, so does  $I_D$ .



### JFET Operating Characteristics: Saturation

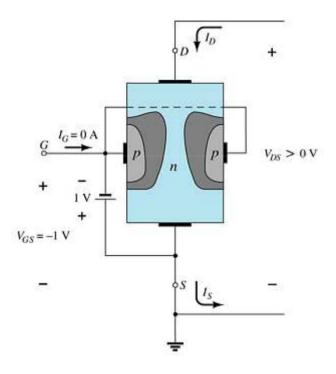
#### At the pinch-off point:

- Any further increase in V<sub>GS</sub> does not produce any increase in I<sub>D</sub>. V<sub>GS</sub> at pinch-off is denoted as V<sub>D</sub>.
- I<sub>D</sub> is at saturation or maximum. It is referred to as I<sub>DSS</sub>.
- The ohmic value of the channel is maximum.



### **JFET Operating Characteristics**

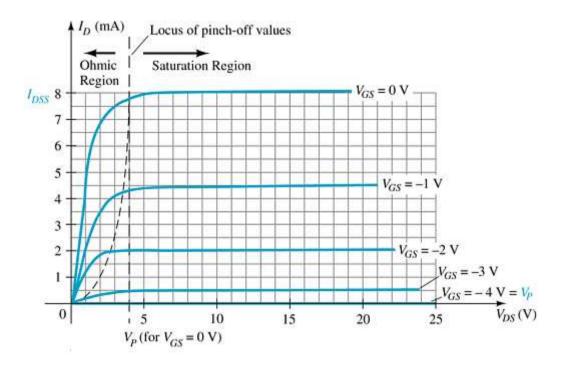
As V<sub>GS</sub> becomes more negative, the depletion region increases.



### **JFET Operating Characteristics**

As V<sub>GS</sub> becomes more negative:

- The JFET experiences pinch-off at a lower voltage (V<sub>P</sub>).
- I<sub>D</sub> decreases (I<sub>D</sub> < I<sub>DSS</sub>) even though V<sub>DS</sub> is increased.
- Eventually I<sub>D</sub> reaches 0 A.
   V<sub>GS</sub> at this point is called V<sub>D</sub>



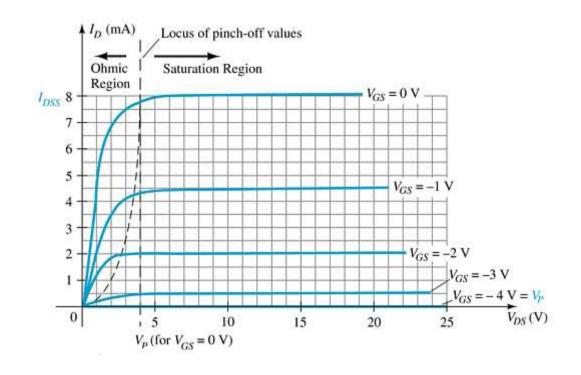
Also notesthat at high levels of  $V_{\text{DS}}$  the JFET reaches a breakdown situation.  $I_{\text{D}}$  increases uncontrollably if  $V_{\text{DS}} > V_{\text{DSmax}}$ 

### JFET Operating Characteristics: Voltage-Controlled Resistor

The region to the left of the pinch-off point is called the ohmic region.

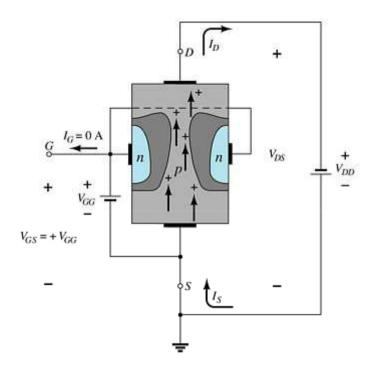
The JFET can be used as a variable resistor, where  $V_{GS}$  controls the drain-source resistance ( $r_d$ ). As  $V_{GS}$  becomes more negative, the resistance ( $r_d$ ) increases.

$$r_{d} = \frac{r_{o}}{\left(1 - \frac{V_{GS}}{V_{P}}\right)^{2}}$$



### p-Channel JFETS

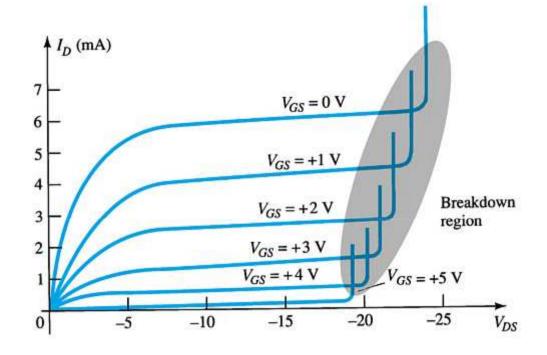
The *p*-channel JFET behaves the same as the *n*-channel JFET, except the voltage polarities and current directions are reversed.



### p-Channel JFET Characteristics

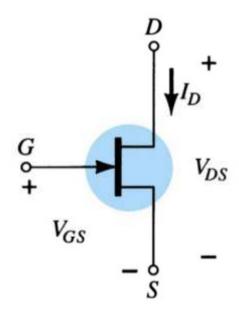
As V<sub>GS</sub> increases more positively

- The depletion zone increases
- $I_D$  decreases  $(I_D < I_{DSS})$
- Eventually  $I_D = 0 A$



Also note that at high levels of  $V_{DS}$  the JFET reaches a breakdown situation:  $I_{D}$  increases uncontrollably if  $V_{DS} > V_{DSmax}$ .

# N-Channel JFET Symbol



#### **JFET Transfer Characteristics**

The transfer characteristic of input-to-output is not as straightforward in a JFET as it is in a BJT.

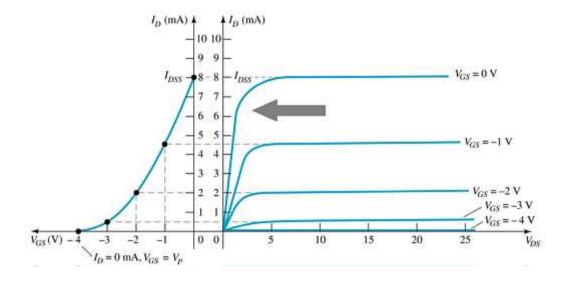
In a BJT,  $\beta$  indicates the relationship between  $I_B$  (input) and  $I_C$  (output).

In a JFET, the relationship of  $V_{GS}$  (input) and  $I_D$  (output) is a little more complicated:

$$I_{\mathbf{D}} = I_{\mathbf{DSS}} \left( 1 - \frac{V_{\mathbf{GS}}}{V_{\mathbf{P}}} \right)^{2}$$

#### **JFET Transfer Curve**

This graph shows the value of  $I_D$  for a given value of  $V_{GS}$ .



### Plotting the JFET Transfer Curve

Using I<sub>DSS</sub> and Vp (V<sub>GS(off)</sub>) values found in a specification sheet, the transfer curve can be plotted according to these three steps:

#### Step 1

$$I_D = I_{DSS} \bigg( 1 - \frac{V_{GS}}{V_P} \bigg)^2$$
 Solving for  $V_{GS} = 0V$  
$$I_D = I_{DSS}$$

$$I_D = I_{DSS} \bigg(1 - \frac{V_{GS}}{V_P}\bigg)^2$$
 Solving for  $V_{GS} = V_p \; (V_{GS(off)}) \; I_D = 0A$ 

Solving for 
$$V_{GS} = 0V$$
 to  $V_p$   $I_D = I_{DSS} \left(1 - \frac{V_{GS}}{V_P}\right)^2$ 



### **JFET Specifications Sheet**

#### **Electrical Characteristics**

ELECTRICAL CHARACTERISTICS (TA = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Gate-Source Breakdown Voltage (I <sub>G</sub> = -10 μAdc, V <sub>DS</sub> = 0)		V <sub>(BR)GSS</sub>	-25	0+1	-	Vdc
Gate Reverse Current $(V_{GS} = -15 \text{ Vdc}, V_{DS} = 0)$ $(V_{GS} = -15 \text{ Vdc}, V_{DS} = 0, T_A = 100^{\circ}\text{C})$		1 <sub>GSS</sub>		14	-1.0 -200	nAdo
Gate Source Cutoff Voltage (V <sub>DS</sub> = 15 Vdc, I <sub>D</sub> = 10 nAdc)	2N5457	V <sub>GS(off)</sub>	-0.5	-	-6.0	Vdc
Gate Source Voltage $(V_{DS} = 15 \text{ Vdc}, I_D = 100 \ \mu\text{Adc})$	2N5457	V <sub>GS</sub>	-	-2.5	-	Vde
ON CHARACTERISTICS  Zero-Gate-Voltage Drain Current*  (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0)	2N5457	I <sub>DSS</sub>	1.0	3.0	5.0	mAde
SMALL-SIGNAL CHARACTERISTICS Forward Transfer Admittance Common Source*		lyed				gemho
$(V_{DS} = 15 \text{ Vdc}, V_{GS} = 0, f = 1.0 \text{ kHz})$	2N5457	1219	1000	-	5000	дино
Output Admittance Common Source* (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0, f = 1.0 kHz)		lyod	( <del>4</del> )	10	50	μmho
Input Capacitance (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0, f = 1.0 MHz)		Ciss	-	4.5	7.0	pF
Reverse Transfer Capacitance		C <sub>rss</sub>		-	9300	pF

 $(V_{DS} = 15 \text{ Vdc}, V_{GS} = 0, f = 1.0 \text{ MHz})$ \*Pulse Test: Pulse Width \$630 ms; Duty Cycle \$10%

Electronic Devices and Circuit Theory, 10/e

Robert L. Boylestad and Louis Nashelsky



### **JFET Specifications Sheet**

#### **Maximum Ratings**

#### MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltage	V <sub>DS</sub>	25	Vdc
Drain-Gate Voltage	V <sub>DG</sub>	25	Vdc
Reverse Gate-Source Voltage	V <sub>GSR</sub>	-25	Vdc
Gate Current	I <sub>G</sub>	10	mAdc
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	P <sub>D</sub>	310 2.82	mW/C
Junction Temperature Range	Tj	125	.c
Storage Channel Temperature Range	Tug	-65 to +150	.c



Refer to 2N4220 for graphs.

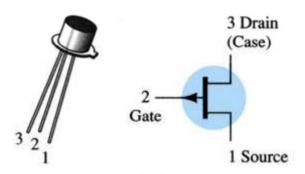
#### more...



#### **Case and Terminal Identification**

2N2844

CASE 22-03, STYLE 12 TO-18 (TO-206AA)



JFETs GENERAL PURPOSE P-CHANNEL

### **Testing JFETs**

Curve Tracer

A curve tracer displays the  $I_D$  versus  $V_{DS}$  graph for various levels of  $V_{GS}$ .

Specialized FET Testers

These testers show I<sub>DSS</sub> for the JFET under test.

#### **MOSFETs**

MOSFETs have characteristics similar to JFETs and additional characteristics that make then very useful.

There are two types of MOSFETs:

- Depletion-Type
- Enhancement-Type

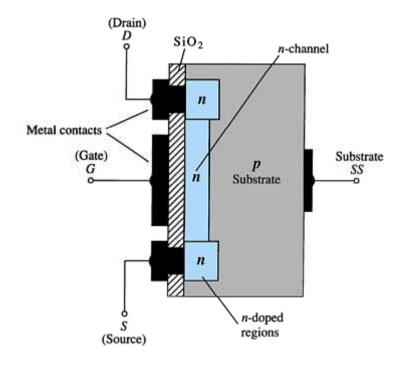


### Depletion-Type MOSFET Construction

The Drain (D) and Source (S) connect to the to *n*-doped regions. These *n*doped regions are connected via an *n*-channel. This *n*-channel is connected to the Gate (G) via a thin insulating layer of SiO<sub>2</sub>.

The *n*-doped material lies on a *p*doped substrate that may have an additional terminal connection called Substrate (SS).

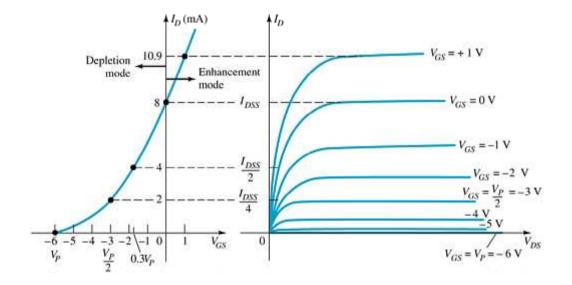
Robert L. Boylestad and Louis Nashelsky



### **Basic MOSFET Operation**

#### A depletion-type MOSFET can operate in two modes:

- Depletion mode
- Enhancement mode



# D-Type MOSFET in Depletion Mode

#### **Depletion Mode**

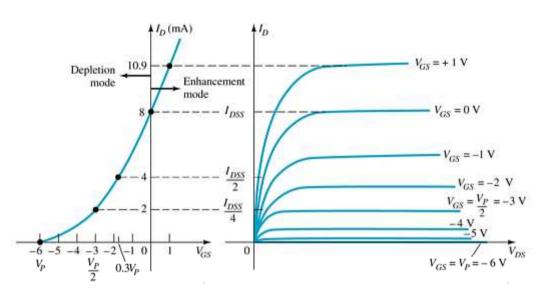
The characteristics are similar to a JFET.



• When  $V_{GS} < 0 \text{ V}$ ,  $I_D < I_{DSS}$ 

• The formula used to plot the transfer curve still applies:

$$I_{D} = I_{DSS} \left( 1 - \frac{V_{GS}}{V_{P}} \right)^{2}$$

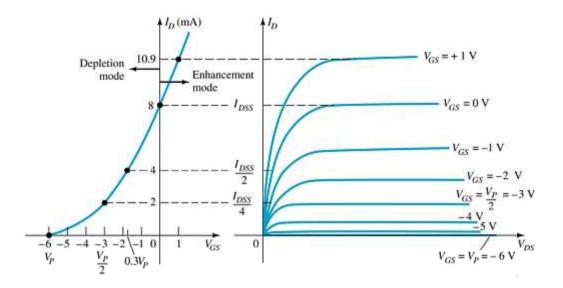


### D-Type MOSFET in Enhancement Mode

#### **Enhancement Mode**

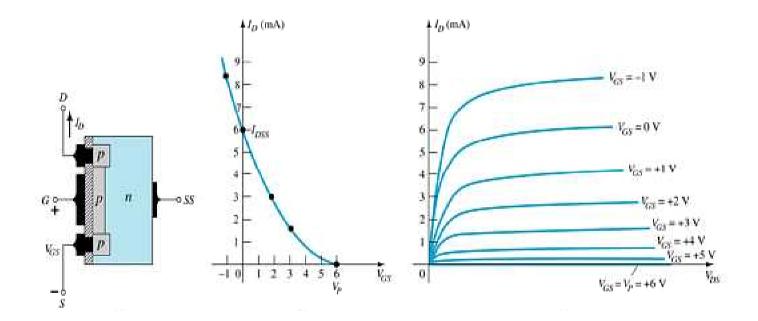
- V<sub>GS</sub> > 0 V
- I<sub>D</sub> increases above I<sub>DSS</sub>
- The formula used to plot the transfer curve still applies:

$$I_{D} = I_{DSS} \left( 1 - \frac{V_{GS}}{V_{P}} \right)^{2}$$

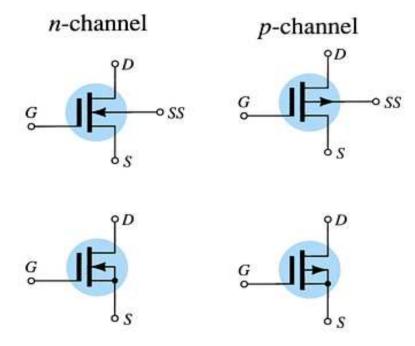


Note that  $V_{GS}$  is now a positive polarity

# p-Channel D-Type MOSFET



# **D-Type MOSFET Symbols**



### **Specification Sheet**

#### **Maximum Ratings**

#### MAXIMUM RATINGS

Rating	Symbol	Value	Unit	
Drain-Source Voltage 2N3797	V <sub>DS</sub>	20	Vdc	
Gate-Source Voltage	Vcs	±10	Vdc	
Drain Current	I <sub>D</sub>	20	mAdc	
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	Po	200 1.14	mW/C	
Junction Temperature Range	T <sub>J</sub>	+175	.c	
Storage Channel Temperature Range	Tur	-65 to +200	,C	



more...



### **Specification Sheet**

#### **Electrical Characteristics**

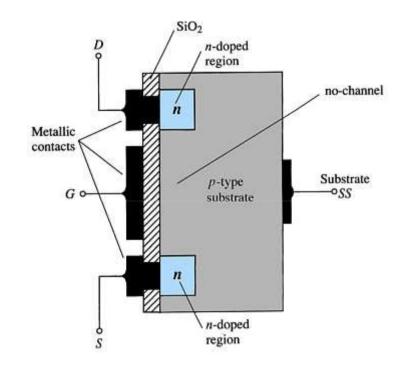
Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain Source Breakdown Voltage (V <sub>CS</sub> = -7.0 V, I <sub>D</sub> = 5.0 μA)	2N3797	V <sub>inestisx</sub>	20	25	- 2	Vdc
Gate Reverse Current (1) $(V_{GS} = -10 \text{ V}, V_{DS} = 0)$ $(V_{GS} = -10 \text{ V}, V_{DS} = 0, T_A = 150^{\circ}\text{C})$		l <sub>css</sub>	1.7		1.0 200	pAde
Gate Source Cutoff Voltage (I <sub>D</sub> = 2.0 μA, V <sub>DS</sub> = 10 V)	2N3797	V <sub>GS(off)</sub>	44	-5.0	-7.0	Vdc
Drain-Gate Reverse Current (1) $(V_{DG} = 10 \text{ V}, I_S = 0)$		1 <sub>000</sub>			1.0	pAdc
ON CHARACTERISTICS						
Zero-Gute-Voltage Drain Current $(V_{DS} = 10 \text{ V}, V_{GS} = 0)$	2N3797	loss	2.0	2.9	6.0	mAde
On-State Drain Current $(V_{DS} = 10 \text{ V}, V_{GS} = +3.5 \text{ V})$	2N3797	I <sub>EN(on)</sub>	9.0	14	18	mAde
SMALL-SIGNAL CHARACTERISTICS						
Forward Transfer Admittance $(V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1.0 \text{ kHz})$	2N3797	lynl	1500	2300	3000	μmho
$(V_{OS} = 10 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz})$	2N3797	C11010	1500	-	-	
Output Admittance $(I_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1.0 \text{ kHz})$	2N3797	Yosl		27	60	μmho
Input Capacitance $(V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz})$	2N3797	Cim	:=	6.0	8.0	pF
Reverse Transfer Capacitance $(V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz})$		Cris	31	0.5	0.8	pF
FUNCTIONAL CHARACTERISTICS						
Noise Figure $(V_{fix} = 10 \text{ V}, V_{fix} = 0, f = 1.0 \text{ kHz}, R_x = 3 \text{ megohins})$		NF		3.8	-	dB

This value of current includes both the FET leakage current as well as the leakage current associated with the test socket and fixture
when measured under best attainable conditions.



### E-Type MOSFET Construction

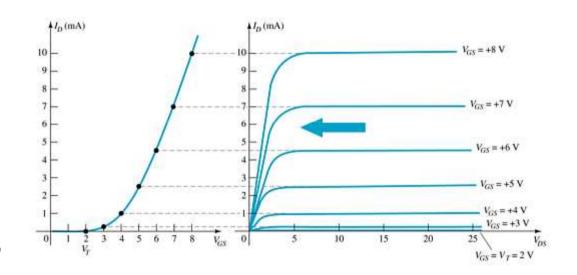
- The Drain (D) and Source (S)
   connect to the to n-doped regions.
   These n-doped regions are
   connected via an n-channel
- The Gate (G) connects to the pdoped substrate via a thin insulating layer of SiO<sub>2</sub>
- There is no channel
- The n-doped material lies on a pdoped substrate that may have an additional terminal connection called the Substrate (SS)



### Basic Operation of the E-Type MOSFET

#### The enhancement-type MOSFET operates only in the enhancement mode.

- V<sub>GS</sub> is always positive
- As V<sub>GS</sub> increases, I<sub>D</sub> increases
- As V<sub>GS</sub> is kept constant and V<sub>DS</sub> is increased, then I<sub>D</sub> saturates (I<sub>DSS</sub>) and the saturation level, V<sub>DSsat</sub> is reached





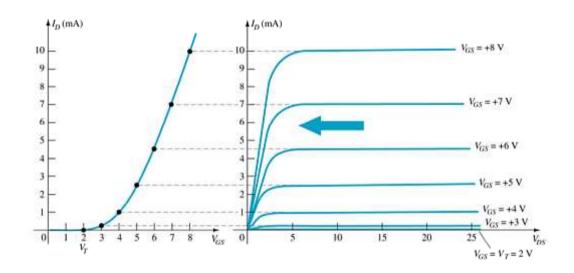
# E-Type MOSFET Transfer Curve

To determine I<sub>D</sub> given V<sub>GS</sub>:

$$I_{D} = k(V_{GS} - V_{T})^{2}$$

#### Where:

V<sub>T</sub> = threshold voltage or voltage at which the MOSFET turns on



k, a constant, can be determined by using values at a specific point and the formula:

$$k = \frac{I_{D(ON)}}{(V_{GS(ON)} - VT)^2}$$

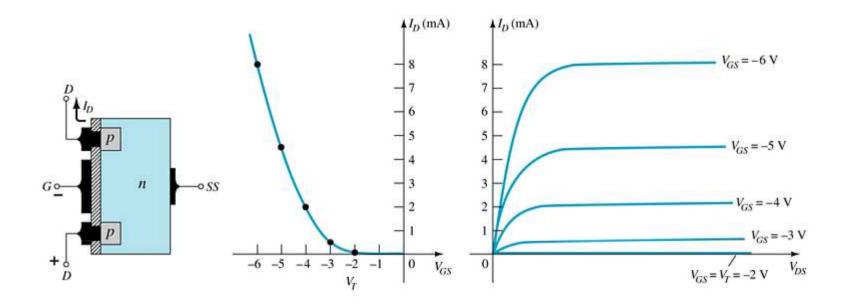
Electronic Devices and Circuit Theory, 10/e

Robert L. Boylestad and Louis Nashelsky

#### $V_{\text{DSsat}}$ can be calculated by:

$$V_{Dsat} = V_{GS} - V_{T}$$

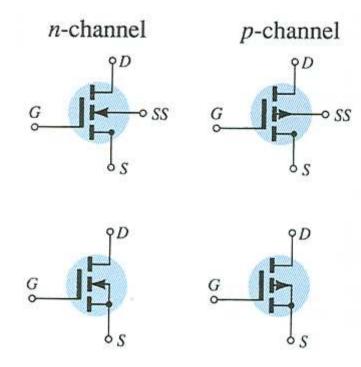
# p-Channel E-Type MOSFETs



The p-channel enhancement-type MOSFET is similar to the nchannel, except that the voltage polarities and current directions are reversed.

Copyright ©2009 by Pearson Education, Inc.

# **MOSFET Symbols**



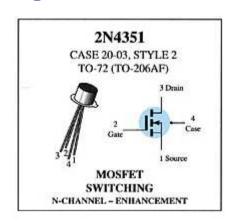
### **Specification Sheet**

#### **Maximum Ratings**

#### MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltage	V <sub>DS</sub>	25	Vdc
Drain-Gate Voltage	V <sub>DG</sub>	30	Vdc
Gate-Source Voltage*	V <sub>GS</sub>	30	Vdc
Drain Current	Ip	30	mAde
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	PD	300 1.7	mW mW/C
Junction Temperature Range	T	175	·c
Storage Temperature Range	Tate	-65 to +175	°C

<sup>\*</sup> Transient potentials of ± 75 Volt will not cause gate-oxide failure.



#### more...



# **Specification Sheet**

#### **Electrical Characteristics**

	Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTI	cs				
Drain-Source Breakdown $V_{GS} = 10 \mu A$ , $V_{GS} = 0$		V <sub>(BR)DSX</sub>	25	=	Vde
Zero-Gate-Voltage Drain C (V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0)		I <sub>DSS</sub>	-	10 10	nAdo µAdo
Gate Reverse Current (V <sub>GS</sub> = ± 15 Vdc, V <sub>DS</sub>	= 0)	I <sub>coss</sub>	(+)	± 10	pAdo
ON CHARACTERISTIC	S				
Gate Threshold Voltage (V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10)	IA)	V <sub>GS(Th)</sub>	1.0	5	Vdc
Drain-Source On-Voltage (1 <sub>D</sub> = 2.0 mA, V <sub>GS</sub> = 1	0V)	V <sub>DS(on)</sub>	300	1.0	v
On-State Drain Current (V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 10	) V)	I <sub>D(on)</sub>	3.0	-	mAda
SMALL-SIGNAL CHAR	ACTERISTICS				
Forward Transfer Admittar $(V_{DS} = 10 \text{ V}, I_D = 2.0)$		ly <sub>fs</sub>	1000	- 4	μmbe
Input Capacitance (V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0,	f = 140 kHz)	Ciss	+	5.0	pF
Reverse Transfer Capacitar $(V_{DS} = 0, V_{GS} = 0, f =$		C <sub>rss</sub>	1	1.3	pF
Drain-Substrate Capacitane (V <sub>D(SUB)</sub> = 10 V, f = 1		C <sub>d(sub)</sub>		5,0	pF
Drain-Source Resistance (V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0, f	= 1.0 kHz)	f <sub>ds(os)</sub>	121	300	ohms
SWITCHING CHARAC	FERISTICS			(e — n	
Turn-On Delay (Fig. 5)	C = 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2	L <sub>d1</sub>	200	45	ns
Rise Time (Fig. 6)	1 <sub>D</sub> = 2.0 mAdc, V <sub>DS</sub> = 10 Vdc, (V <sub>GS</sub> = 10 Vdc) (See Figure 9: Times Circuit Determined)	1,	-	65	ns
Turn-Off Delay (Fig. 7)		L <sub>d2</sub>	-	60	ns
Fall Time (Fig. 8)		t <sub>f</sub>	-	100	ns



### Handling MOSFETs

MOSFETs are very sensitive to static electricity. Because of the very thin SiO<sub>2</sub> layer between the external terminals and the layers of the device, any small electrical discharge can create an unwanted conduction.

#### **Protection**

- Always transport in a static sensitive bag
- Always wear a static strap when handling MOSFETS
- •
- Apply voltage limiting devices between the gate and source, such as back-to-back Zeners to limit any transient voltage.

#### **VMOS Devices**

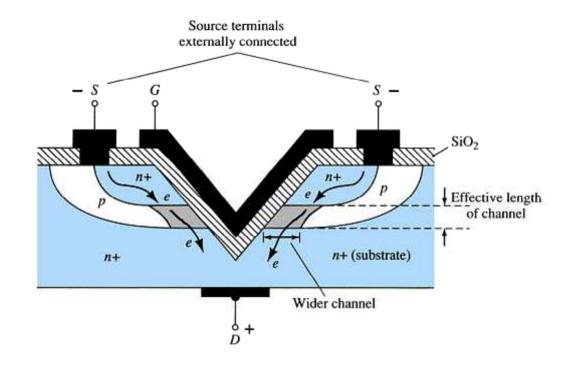
VMOS (vertical MOSFET) increases the surface area of the device.

#### **Advantages**

- VMOS devices handle higher currents by providing more surface area to dissipate the heat.
- VMOS devices also have faster switching times.

Electronic Devices and Circuit Theory, 10/e

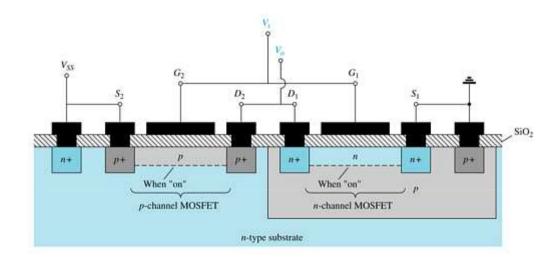
Robert L. Boylestad and Louis Nashelsky





#### **CMOS Devices**

CMOS (complementary MOSFET) uses a *p*-channel and *n*-channel MOSFET; often on the same substrate as shown here.



#### **Advantages**

- Useful in logic circuit designs
- Higher input impedance
- Faster switching speeds
- Lower operating power levels

# **Summary Table**

